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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, IrDA, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	110
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	640K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 3.6V
Data Converters	A/D 22x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	145-TFLGA
Supplier Device Package	145-TFLGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs5d97c2a01clk-ac0

Table 1.3 System (3 of 3)

Feature	Functional description
Independent Watchdog Timer (IWDT)	The IWDT consists of a 14-bit down-counter that must be serviced periodically to prevent counter underflow. The IWDT provides functionality to reset the MCU or to generate a non-maskable interrupt or interrupt for a timer underflow. Because the timer operates with an independent, dedicated clock source, it is particularly useful in returning the MCU to a known state as a fail safe mechanism when the system runs out of control. The IWDT can be triggered automatically on a reset, underflow, or refresh error, or by a refresh of the count value in the registers. See section 28, Independent Watchdog Timer (IWDT) in User's Manual.

Table 1.4 Event link

Feature	Functional description
Event Link Controller (ELC)	The ELC uses the interrupt requests generated by various peripheral modules as event signals to connect them to different modules, enabling direct interaction between the modules without CPU intervention. See section 19, Event Link Controller (ELC) in User's Manual.

Table 1.5 Direct memory access

Feature	Functional description
Data Transfer Controller (DTC)	A DTC module is provided for transferring data when activated by an interrupt request. See section 18, Data Transfer Controller (DTC) in User's Manual.
DMA Controller (DMAC)	An 8-channel DMAC module is provided for transferring data without the CPU. When a DMA transfer request is generated, the DMAC transfers data stored at the transfer source address to the transfer destination address. See section 17, DMA Controller (DMAC) in User's Manual.

Table 1.6 External bus interface

Feature	Functional description
External buses	<ul style="list-style-type: none"> • CS area (EXBIU): Connected to the external devices (external memory interface) • SDRAM area (EXBIU): Connected to the SDRAM (external memory interface) • QSPI area (EXBIUT2): Connected to the QSPI (external device interface).

Table 1.7 Timers

Feature	Functional description
General PWM Timer (GPT)	The GPT is a 32-bit timer with 14 channels. PWM waveforms can be generated by controlling the up-counter, down-counter, or up- and down-counter. In addition, PWM waveforms can be generated for controlling brushless DC motors. The GPT can also be used as a general-purpose timer. See section 23, General PWM Timer (GPT) in User's Manual.
Port Output Enable for GPT (POEG)	Use the Port Output Enable for GPT (POEG) function to place the General PWM Timer (GPT) output pins in the output disable state. See section 22, Port Output Enable for GPT (POEG) in User's Manual.
Asynchronous General-Purpose Timer (AGT)	The AGT is a 16-bit timer that can be used for pulse output, external pulse width or period measurement, and counting of external events. This 16-bit timer consists of a reload register and a down-counter. The reload register and the down-counter are allocated to the same address, and can be accessed with the AGT register. See section 25, Asynchronous General-Purpose Timer (AGT) in User's Manual.
Realtime Clock (RTC)	The RTC has two counting modes, calendar count mode and binary count mode, that are controlled by the register settings. For calendar count mode, the RTC has a 100-year calendar from 2000 to 2099 and automatically adjusts dates for leap years. For binary count mode, the RTC counts seconds and retains the information as a serial value. Binary count mode can be used for calendars other than the Gregorian (Western) calendar. See section 26, Realtime Clock (RTC) in User's Manual.

1.5 Pin Functions

Table 1.16 Pin functions (1 of 5)

Function	Signal	I/O	Description
Power supply	VCC	Input	Digital voltage supply pin. This is used as the digital power supply for the respective modules and internal voltage regulator, and used to monitor the voltage of the POR/LVD. Connect to the system power supply. Connect to VSS through a 0.1- μ F smoothing capacitor close to each VCC pin.
	VCL0	-	Connect to VSS through a 0.1- μ F smoothing capacitor close to each VCL pin. Stabilize the internal power supply.
	VCL	-	
	VSS	Input	Ground pin. Connect to the system power supply (0 V).
Clock	VBATT	Input	Backup power pin.
	XTAL	Output	Pins for a crystal resonator. An external clock signal can be input through the EXTAL pin.
	EXTAL	Input	
	XCIN	Input	Input/output pins for the sub-clock oscillator. Connect a crystal resonator between XCOUT and XCIN.
	XCOUT	Output	
	EBCLK	Output	Outputs the external bus clock for external devices.
	SDCLK	Output	Outputs the SDRAM-dedicated clock.
Operating mode control	CLKOUT	Output	Clock output pin.
	MD	Input	Pin for setting the operating mode. The signal level on this pin must not be changed during operation mode transition or release from the reset state.
System control	RES	Input	Reset signal input pin. The MCU enters the reset state when this signal goes low.
CAC	CACREF	Input	Measurement reference clock input pin.
Interrupt	NMI	Input	Non-maskable interrupt request pin.
	IRQ0 to IRQ15	Input	Maskable interrupt request pins.
KINT	KR00 to KR07	Input	A key interrupt can be generated by inputting a falling edge to the key interrupt input pins.
On-chip emulator	TMS	I/O	On-chip emulator or boundary scan pins.
	TDI	Input	
	TCK	Input	
	TDO	Output	
	TCLK	Output	
	TDATA0 to TDATA3	Output	
	SWDIO	I/O	
	SWCLK	Input	
	SWO	Output	
External bus interface	RD	Output	Strobe signal indicating that reading from the external bus interface space is in progress, active low.
	WR	Output	Strobe signal indicating that writing to the external bus interface space is in progress, in 1-write strobe mode, active low.
	WR0 to WR1	Output	Strobe signals indicating that either group of data bus pins (D07 to D00 or D15 to D08) is valid in writing to the external bus interface space, in byte strobe mode, active low.
	BC0 to BC1	Output	Strobe signals indicating that either group of data bus pins (D07 to D00 or D15 to D08) is valid in access to the external bus interface space, in 1-write strobe mode, active low.
	ALE	Output	Address latch signal when address/data multiplexed bus is selected.
	WAIT	Input	Input pin for wait request signals in access to the external space, active low.
	CS0 to CS7	Output	Select signals for CS areas, active low.
	A00 to A23	Output	Address bus.
	D00 to D15	I/O	Data bus.
	A00/D00 to A15/D15	I/O	Address/data multiplexed bus.

Table 1.16 Pin functions (3 of 5)

Function	Signal	I/O	Description
SPI	RSPCKA, RSPCKB	I/O	Clock input/output pin.
	MOSIA, MOSIB	I/O	Input or output pins for data output from the master.
	MISOA, MISOB	I/O	Input or output pins for data output from the slave.
	SSLA0, SSLB0	I/O	Input or output pin for slave selection.
	SSLA1 to SSLA3, SSLB1 to SSLB3	Output	Output pins for slave selection.
QSPI	QSPCLK	Output	QSPI clock output pin.
	QSSL	Output	QSPI slave output pin.
	QIO0 to QIO3	I/O	Data0 to Data3.
CAN	CRX0, CRX1	Input	Receive data.
	CTX0, CTX1	Output	Transmit data.
USBFS	VCC_USB	Input	Power supply pins.
	VSS_USB	Input	Ground pins.
	USB_DP	I/O	D+ I/O pin of the USB on-chip transceiver. Connect this pin to the D+ pin of the USB bus.
	USB_DM	I/O	D- I/O pin of the USB on-chip transceiver. Connect this pin to the D- pin of the USB bus.
	USB_VBUS	Input	USB cable connection monitor pin. Connect this pin to VBUS of the USB bus. The VBUS pin status (connected or disconnected) can be detected when the USB module is operating as a function controller.
	USB_EXICEN	Output	Low-power control signal for external power supply (OTG) chip.
	USB_VBUSEN	Output	VBUS (5 V) supply enable signal for external power supply chip.
	USB_OVRCURA, USB_OVRCURB	Input	Connect the external overcurrent detection signals to these pins. Connect the VBUS comparator signals to these pins when the OTG power supply chip is connected.
	USB_ID	Input	Connect the MicroAB connector ID input signal to this pin during operation in OTG mode.
	VCC_USBHS	Input	Power supply pin.
USBHS	VSS1_USBHS	Input	Ground pin.
	VSS2_USBHS	Input	Ground pin.
	AVCC_USBHS	Input	Analog power supply pin for the USBHS.
	AVSS_USBHS	Input	Analog ground pin for the USBHS. Must be shorted to the PVSS_USBHS pin.
	PVSS_USBHS	Input	PLL circuit ground pin for the USBHS. Must be shorted to the AVSS_USBHS pin.
	USBHS_RREF	I/O	USBHS reference current source pin. Connect this pin to the AVSS_USBHS pin through a 2.2-kΩ resistor (±1%).
	USBHS_DP	I/O	USB bus D+ data pin.
	USBHS_DM	I/O	USB bus D- data pin.
	USBHS_EXICEN	Output	Connect this pin to the OTG power supply IC.
	USBHS_ID	Input	Connect this pin to the OTG power supply IC.
	USBHS_VBUSEN	Output	VBUS power enable signal for USB.
	USBHS_OVRCURA, USBHS_OVRCURB	Input	Overcurrent pin for USB.
	USBHS_VBUS	Input	USB cable connection monitor input pin.

Table 1.16 Pin functions (5 of 5)

Function	Signal	I/O	Description
ADC12	AN000 to AN007, AN016 to AN020	Input	Input pins for the analog signals to be processed by the ADC12.
	AN100 to AN103, AN105 to AN107, AN116 to AN119	Input	
	ADTRG0	Input	Input pins for the external trigger signals that start the A/D conversion.
	ADTRG1	Input	
	PGAVSS000/PGAVS S100	Input	Differential input pins.
DAC12	DA0, DA1	Output	Output pins for the analog signals processed by the D/A converter.
ACMPHS	VCOUT	Output	Comparator output pin.
	IVREF0 to IVREF3	Input	Reference voltage input pins for comparator.
	IVCMP0 to IVCMP2	Input	Analog voltage input pins for comparator.
CTSU	TS00 to TS17	Input	Capacitive touch detection pins (touch pins).
	TSCAP	-	Secondary power supply pin for the touch driver.
I/O ports	P000 to P007	Input	General-purpose input pins.
	P008 to P010, P014, P015	I/O	General-purpose input/output pins.
	P100 to P115	I/O	General-purpose input/output pins.
	P200	Input	General-purpose input pin.
	P201 to P214	I/O	General-purpose input/output pins.
	P300 to P315	I/O	General-purpose input/output pins.
	P400 to P415	I/O	General-purpose input/output pins.
	P500 to P508, P511 to P513	I/O	General-purpose input/output pins.
	P600 to P615	I/O	General-purpose input/output pins.
	P700 to P713	I/O	General-purpose input/output pins.
	P800 to P806	I/O	General-purpose input/output pins.
	P900, P901, P905 to P908	I/O	General-purpose input/output pins.
GLCDC	PA00, PA01, PA08 to PA10	I/O	General-purpose input/output pins.
	PB00, PB01	I/O	General-purpose input/output pins.
	LCD_DATA23 to LCD_DATA00	Output	Data output pins for panel.
	LCD_TCON3 to LCD_TCON0	Output	Output pins for panel timing adjustment.
PDC	LCD_CLK	Output	Panel clock output pin.
	LCD_EXTCLK	Input	Panel clock source input pin.
	PIXCLK	Input	Image transfer clock pin.
	VSYNC	Input	Vertical synchronization signal pin.
	H SYNC	Input	Horizontal synchronization signal pin.
PDC	PIXD0 to PIXD7	Input	8-bit image data pins.
	PCKO	Output	Output pin for dot clock.

1.7 Pin Lists

Pin number				Extbus		Timers		Communication interfaces						Analog		HMI									
BGA176	LQFP176	LGA145	LQFP144	LQFP100		Power, System, Clock, Debug, CAC	I/O port	External bus	SDRAM	AGT	GPT	GPT	RTC	USBFS, CAN	SCL0_A	SPI, QSPI	SIE	Etherc (MII) (2.5 MHz)	Etherc (RMII) (50 MHz)	USBHS	SDHI	ADC12, DAC12, ACM/PHS	CTSU	GLCDC, PDC	
N13_1	N13_1	1	1	-	IRQ0	P400	-	-	AGTIO1	-	GTIOC6A	-	CTX0	SCK4	SCK7	SCL0_A	AUDIO_CLK	ET0_WOL	ET0_WOL	-	-	ADTRG1	-	-	
R15_2	L11_2	2	2	-	IRQ5_DS	P401	-	-	-	GTETRGA	GTIOC6B	-	RTC	SDA0_A	-	-	ET0_M_DC	ET0_M_DC	-	-	-	-	-	-	
P14_3	M13_3	3	3	CACREF	IRQ4_DS	P402	-	-	AGTIO0/AGTIO1	-	-	RTC	CRX0	SCI0_2,4,6,8 (30 MHz)	SCI1_3,5,7,9 (30 MHz)	-	AUDIO_CLK	ET0_M_DIO	ET0_M_DIO	-	-	-	-	VSYNC	-
M12_4	K11_4	4	4	-	-	P403	-	-	AGTIO0/AGTIO1	-	GTIOC3A	RTC	IC1	TXD7/MOSI7/SCL7	CTS7/RTS7/SS7	-	SSIBC_K0_A	ET0_LI_NKSTA	ET0_LI_NKSTA	SD1_DAT7_B	-	-	-	PIXD7	-
M13_5	L12_5	5	5	-	-	P404	-	-	-	GTIOC3B	RTC	IC2	-	-	-	-	SSILR_CK0/SIFS0_A	ET0_EX_OUT	ET0_E_XOUT	SD1_DAT6_B	-	-	-	PIXD6	-
P15_6	L13_6	6	6	-	-	P405	-	-	-	GTIOC1A	-	-	-	-	-	SSITX_D0_A	ET0_TX_EN	RMII0_TXD_E_N_B	SD1_DAT5_B	-	-	-	PIXD5	-	
N14_7	J10_7	7	7	-	-	P406	-	-	-	GTIOC1B	-	-	-	-	-	SSLR3_SSI_RX_D0_A	ET0_RX_ER	RMII0_RXD_E_B	SD1_DAT4_B	-	-	-	PIXD4	-	
N15_8	H10_8	-	-	-	-	P700	-	-	-	GTIOC5A	-	-	-	-	-	MISOB_C	-	ET0_ET_XD01	RMII0_RXDO_B	SD1_DAT3_B	-	-	-	PIXD3	-
M14_9	K12_9	-	-	-	-	P701	-	-	-	GTIOC5B	-	-	-	-	-	MOSIB_C	-	ET0_ET_XD0	REF50_CK0_B	SD1_DAT2_B	-	-	-	PIXD2	-
L12_10	K13_10	-	-	-	-	P702	-	-	-	GTIOC6A	-	-	-	-	-	RSPC_KB_C	-	ET0_ER_XD1	RMII0_RXDO_B	SD1_DAT1_B	-	-	-	PIXD1	-
M15_11	J11_11	-	-	-	-	P703	-	-	-	GTIOC6B	-	-	-	-	-	SSLB0_C	-	ET0_ER_XD0	RMII0_RXD1_B	SD1_DAT0_B	-	VCOUT	-	PIXD0	-
L13_12	H11_12	-	-	-	-	P704	-	-	AGTO0	-	-	CTX0	-	-	-	SSLB1_C	-	ET0_RX_CLK	RMII0_RX_E_R_B	SD1_CLK_B	-	-	-	HSYNC	-
K12_13	G11_13	-	-	-	-	P705	-	-	AGTIO0	-	-	CRX0	-	-	-	SSLB2_C	-	ET0_C_RS	RMII0_CRS_DV_B	SD1_CMD_B	-	-	-	PIXCLK	-
L14_14	-	-	-	-	IRQ7	P706	-	-	-	-	-	-	-	RXD3/MISO3/SCL3	-	-	-	-	USB_HS_OVR_CUR_B	SD1_CD_B	-	-	-	-	-
L15_15	-	-	-	-	IRQ8	P707	-	-	-	-	-	-	-	TXD3/MOSI3/SDA3	-	-	-	-	USB_HS_OVR_CUR_A	SD1_WP_B	-	-	-	-	-
J12_16	-	-	-	-	-	PB00	-	-	-	-	-	-	-	SCK3	-	-	-	-	USB_HS_VBU_SEN	-	-	-	-	-	-
K13_17	-	-	-	-	-	PB01	-	-	-	-	-	-	-	CTS3_RTS3_SS3	-	-	-	-	USB_HS_VBU_S	-	-	-	-	-	-
K14_18	J12_14	8	VBATT	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
K15_19	J13_15	9	VCL0	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
J15_20	H13_16	10	XCIN	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
J14_21	H12_17	11	XCOUNT	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
J13_22	F12_18	12	VSS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
H14_23	G12_19	13	XTAL	IRQ2	P213	-	-	-	-	GTETRGC	GTIOC0A	-	-	TXD1/MOSI1/SDA1	-	-	-	-	ADTRG1	-	-	-	-	-	-
H15_24	G13_20	14	EXTAL	IRQ3	P212	-	-	-	AGTEE1	GTETRGD	GTIOC0B	-	-	RXD1/MISO1/SCL1	-	-	-	-	-	-	-	-	-	-	-
H12_25	F13_21	15	VCC	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
H13_26	-	-	-	AVCC_U_SBHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
G13_27	-	-	-	USBHS_RREF	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
G14_28	-	-	-	AVSS_U_SBHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
G15_29	-	-	-	PVSS_U_SBHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
G12_30	-	-	-	VSS2_U_SBHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
F15_31	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	USB_HS_DM	-	-	-	-	-	-	
F14_32	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	USB_HS_DP	-	-	-	-	-	-	
F12_33	-	-	-	VSS1_U_SBHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
F13_34	-	-	-	VCC_US_BHS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	
E15_35	-	-	-	-	P708	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	

2. Electrical Characteristics

Unless otherwise specified, the electrical characteristics of the MCU are defined under the following conditions:

$VCC = AVCC0 = VCC_USB = VBATT = 2.7$ to 3.6 V, $2.7 \leq VREFH/VREFL \leq AVCC0$, $VCC_USBHS = AVCC_USBHS = 3.0$ to 3.6 V, $VSS = AVSS0 = VREFL/VREFH = VSS_USB = VSS1_USBHS = VSS2_USBHS = PVSS_USBHS = AVSS_USBHS = 0$ V, $T_a = Topr$

Figure 2.1 shows the timing conditions.

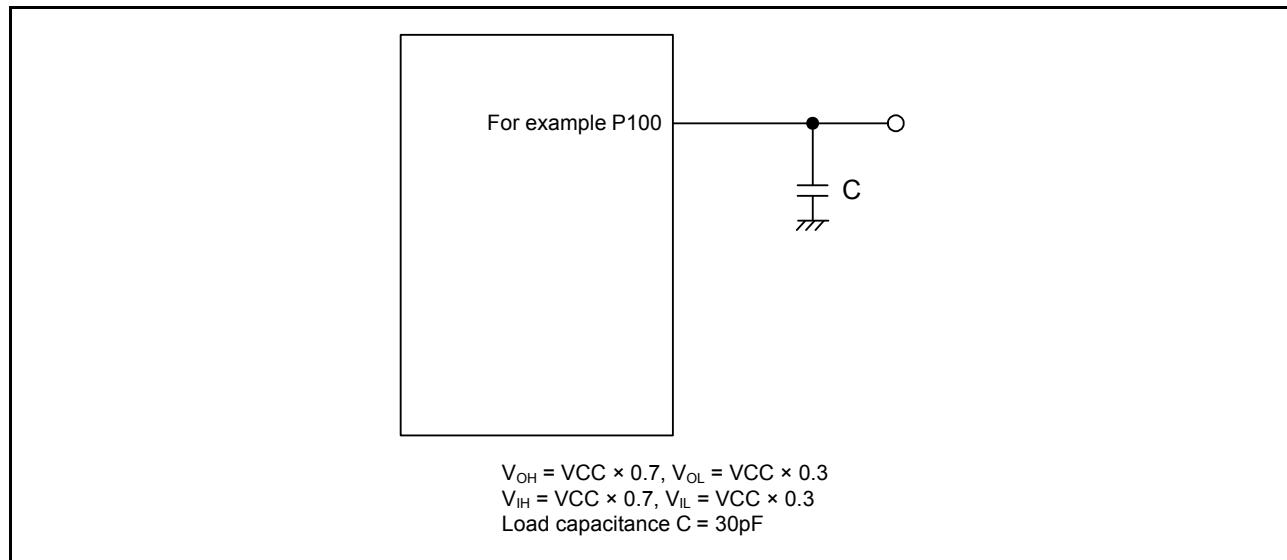


Figure 2.1 Input or output timing measurement conditions

The measurement conditions of timing specification in each peripherals are recommended for the best peripheral operation, however make sure to adjust driving abilities of each pins to meet your conditions.

2.1 Absolute Maximum Ratings

Table 2.1 Absolute maximum ratings

Item	Symbol	Value	Unit
Power supply voltage	VCC , VCC_USB *2	-0.3 to +4.0	V
VBATT power supply voltage	$VBATT$	-0.3 to +4.0	V
Input voltage (except for 5V-tolerant ports*1)	V_{in}	-0.3 to $VCC + 0.3$	V
Input voltage (5V-tolerant ports*1)	V_{in}	-0.3 to + $VCC + 4.0$ (max 5.8)	V
Reference power supply voltage	$VREFH/VREFL$	-0.3 to $VCC + 0.3$	V
Analog power supply voltage	$AVCC0$ *2	-0.3 to +4.0	V
USBHS power supply voltage	VCC_USBHS	-0.3 to +4.0	V
USBHS analog power supply voltage	$AVCC_USBHS$	-0.3 to +4.0	V
Analog input voltage	V_{AN}	-0.3 to $AVCC0 + 0.3$	V
Operating temperature*3,*4,*5	T_{opr}	-40 to +85 -40 to +105	°C
Storage temperature	T_{stg}	-55 to +125	°C

Caution: Permanent damage to the MCU might result if absolute maximum ratings are exceeded.

Note 1. Ports P205, P206, P400, P401, P407 to P415, P511, P512, P708 to P713, and PB01 are 5V-tolerant.

Note 2. Connect $AVCC0$ and VCC_USB to VCC .

Note 3. See section 2.2.1, T_j/T_a Definition.

Note 4. Contact a Renesas Electronics sales office for information on derating operation when $T_a = +85^\circ\text{C}$ to $+105^\circ\text{C}$. Derating is the systematic reduction of load for improved reliability.

Note 5. The upper limit of operating temperature is 85°C or 105°C , depending on the product. For details, see section 1.3, Part Numbering.

2.2.2 I/O V_{IH} , V_{IL} **Table 2.4** I/O V_{IH} , V_{IL}

Item	Symbol	Min	Typ	Max	Unit	
Input voltage (except for Schmitt trigger input pins)	V_{IH}	$VCC \times 0.8$	-	-	V	
	V_{IL}	-	-	$VCC \times 0.2$		
	V_{IH}	$VCC \times 0.7$	-	-		
	V_{IL}	-	-	$VCC \times 0.3$		
	V_{IH}	2.3	-	-		
	V_{IL}	-	-	$VCC \times 0.2$		
	V_{IH}	2.1	-	-		
	V_{IL}	-	-	0.8		
	V_{IH}	2.1	-	$VCC + 3.6$ (max 5.8)		
	V_{IL}	-	-	0.8		
Schmitt trigger input voltage	V_{IH}	$VCC \times 0.7$	-	-		
	V_{IL}	-	-	$VCC \times 0.3$		
	ΔV_T	$VCC \times 0.05$	-	-		
	V_{IH}	$VCC \times 0.7$	-	$VCC + 3.6$ (max 5.8)		
	V_{IL}	-	-	$VCC \times 0.3$		
	ΔV_T	$VCC \times 0.05$	-	-		
	V_{IH}	$VCC \times 0.8$	-	$VCC + 3.6$ (max 5.8)		
	V_{IL}	-	-	$VCC \times 0.2$		
	ΔV_T	$VCC \times 0.05$	-	-		
	RTCIC0, RTCIC1, RTCIC2	When using the Battery Backup Function	V_{IH}	$V_{BATT} \times 0.8$		
			V_{IL}	-		
			ΔV_T	$V_{BATT} \times 0.05$		
		When VCC power supply is selected	V_{IH}	$VCC \times 0.8$		
			V_{IL}	-		
			ΔV_T	$VCC \times 0.05$		
	When not using the Battery Backup Function		V_{IH}	$VCC \times 0.8$		
			V_{IL}	-		
			ΔV_T	$VCC \times 0.05$		
			V_{IH}	$VCC \times 0.8$		
			V_{IL}	-		
			ΔV_T	$VCC \times 0.05$		
Ports	Other input pins* ⁴			$VCC \times 0.8$		
				-		
				$VCC \times 0.2$		
				$VCC \times 0.05$		
	5V-tolerant ports* ^{5, *7}			$VCC \times 0.8$		
				-		
				$VCC \times 0.2$		
	Other input pins* ⁶			$VCC \times 0.8$		
				-		
				$VCC \times 0.2$		

Note 1. SCL0_B (P204), SCL1_B, SDA1_B (total 3 pins).

Note 2. SCL0_A, SDA0_A, SCL0_B (P408), SDA0_B, SCL1_A, SDA1_A, SCL2, SDA2 (total 8 pins).

Note 3. RES and peripheral function pins associated with P205, P206, P400, P401, P407 to P415, P511, P512, P708 to P713, PB01 (total 23 pins).

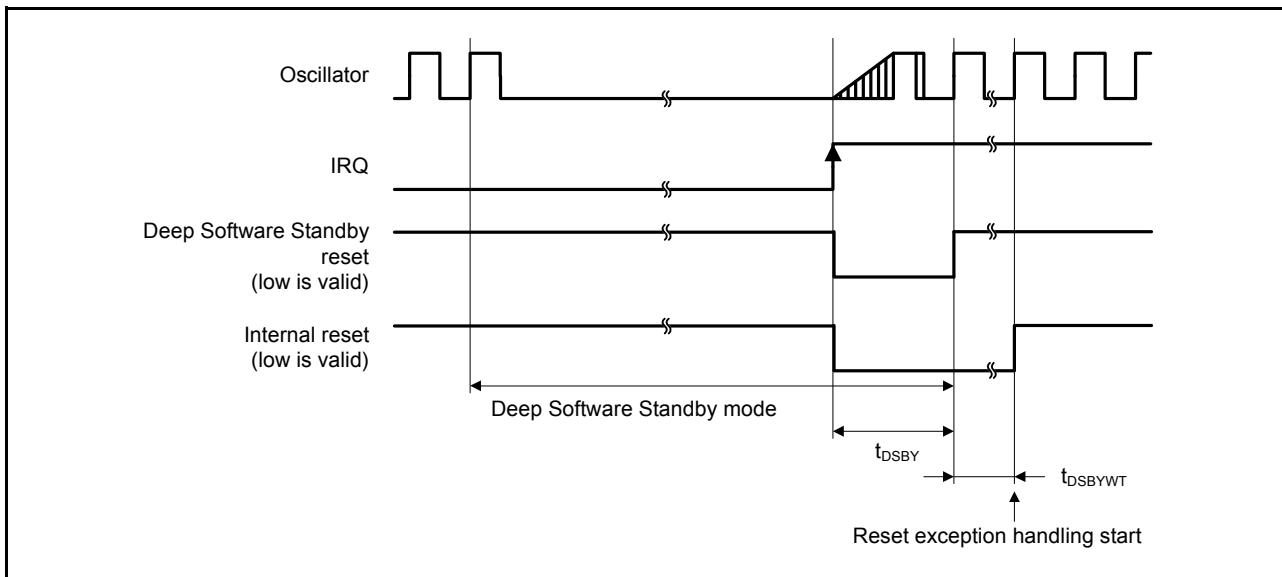
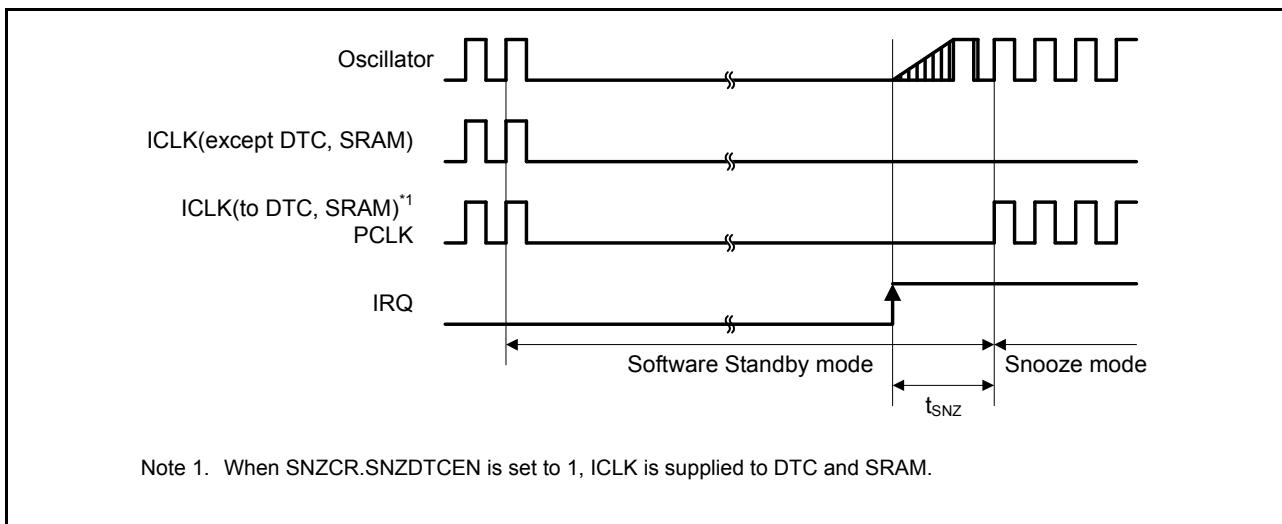


Figure 2.12 Deep Software Standby mode cancellation timing



Note 1. When SNZCR.SNZDTCCEN is set to 1, ICLK is supplied to DTC and SRAM.

Figure 2.13 Recovery timing from Software Standby mode to Snooze mode

2.3.5 NMI and IRQ Noise Filter

Table 2.17 NMI and IRQ noise filter

Item	Symbol	Min	Typ	Max	Unit	Test conditions	
NMI pulse width	t_{NMIW}	200	-	-	ns	NMI digital filter disabled	$t_{Pcyc} \times 2 \leq 200$ ns
		$t_{Pcyc} \times 2^{*1}$	-	-			$t_{Pcyc} \times 2 > 200$ ns
		200	-	-	ns	NMI digital filter enabled	$t_{NMICK} \times 3 \leq 200$ ns
		$t_{NMICK} \times 3.5^{*2}$	-	-			$t_{NMICK} \times 3 > 200$ ns
IRQ pulse width	t_{IRQW}	200	-	-	ns	IRQ digital filter disabled	$t_{Pcyc} \times 2 \leq 200$ ns
		$t_{Pcyc} \times 2^{*1}$	-	-			$t_{Pcyc} \times 2 > 200$ ns
		200	-	-	ns	IRQ digital filter enabled	$t_{IRQCK} \times 3 \leq 200$ ns
		$t_{IRQCK} \times 3.5^{*3}$	-	-			$t_{IRQCK} \times 3 > 200$ ns

Note: 200 ns minimum in Software Standby mode.

Note 1. t_{Pcyc} indicates the PCLKB cycle.

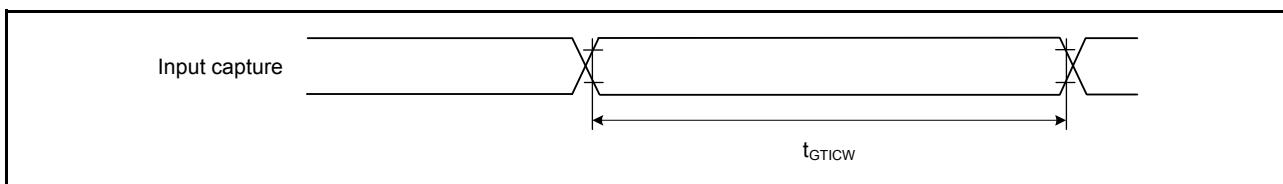


Figure 2.32 GPT32 input capture timing

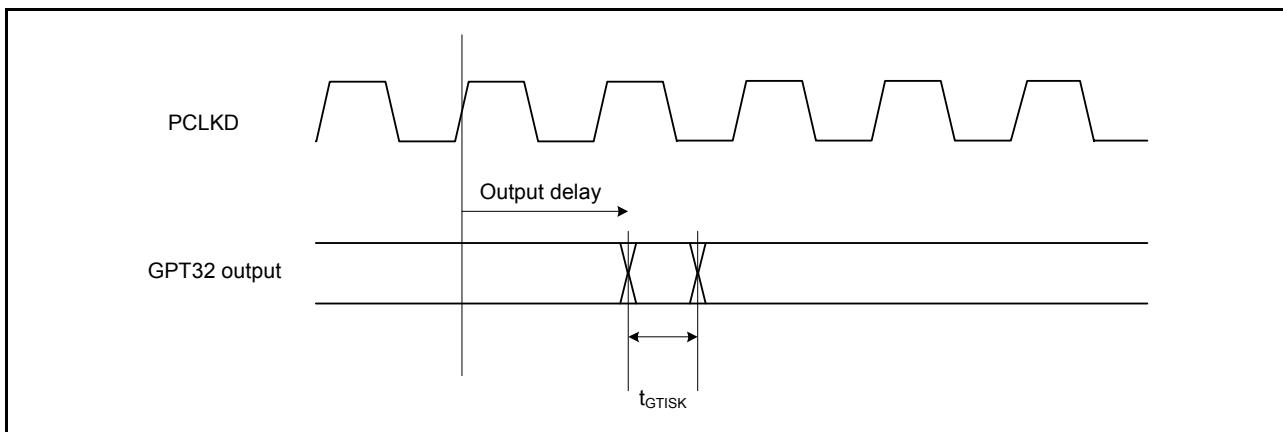


Figure 2.33 GPT32 output delay skew

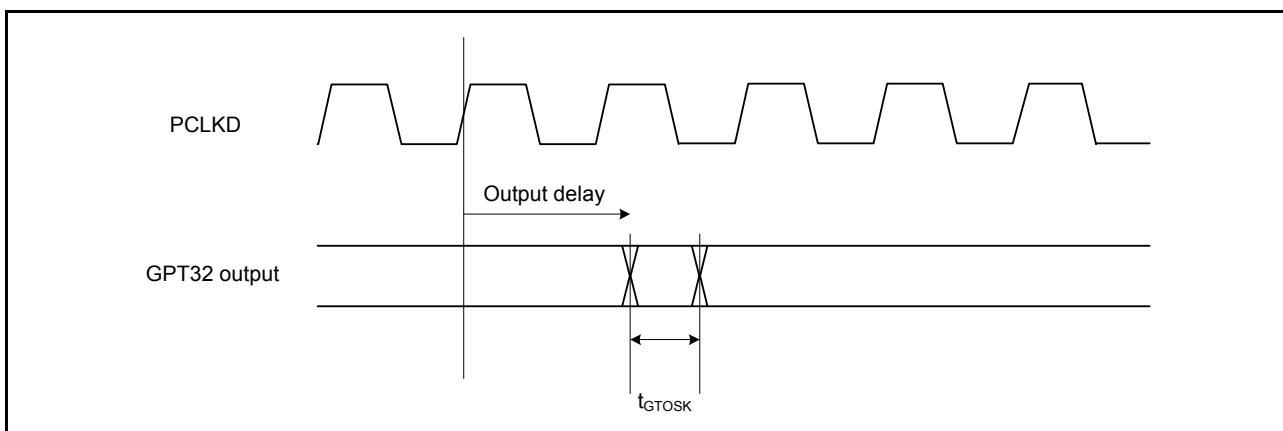


Figure 2.34 GPT32 output delay skew for OPS

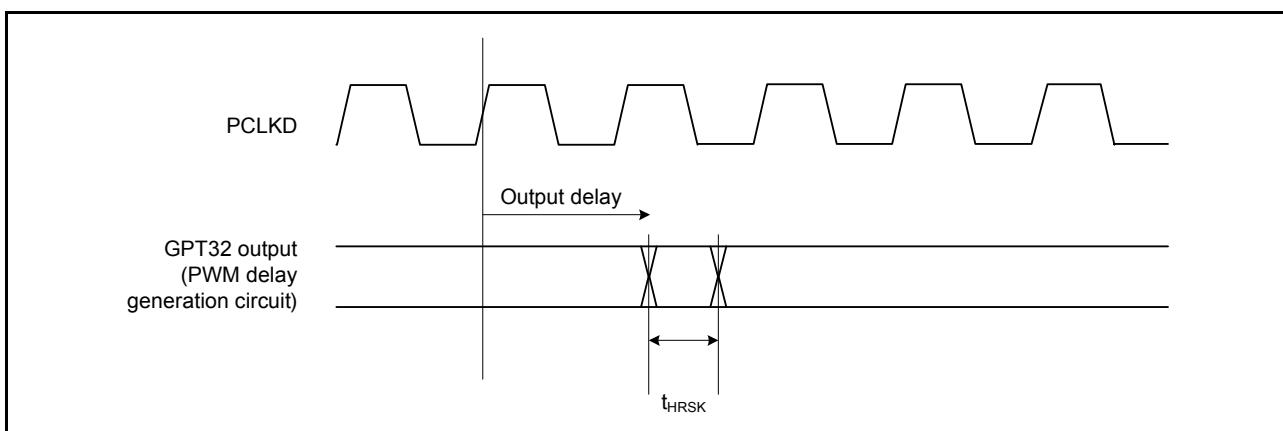


Figure 2.35 GPT32 (PWM Delay Generation Circuit) output delay skew

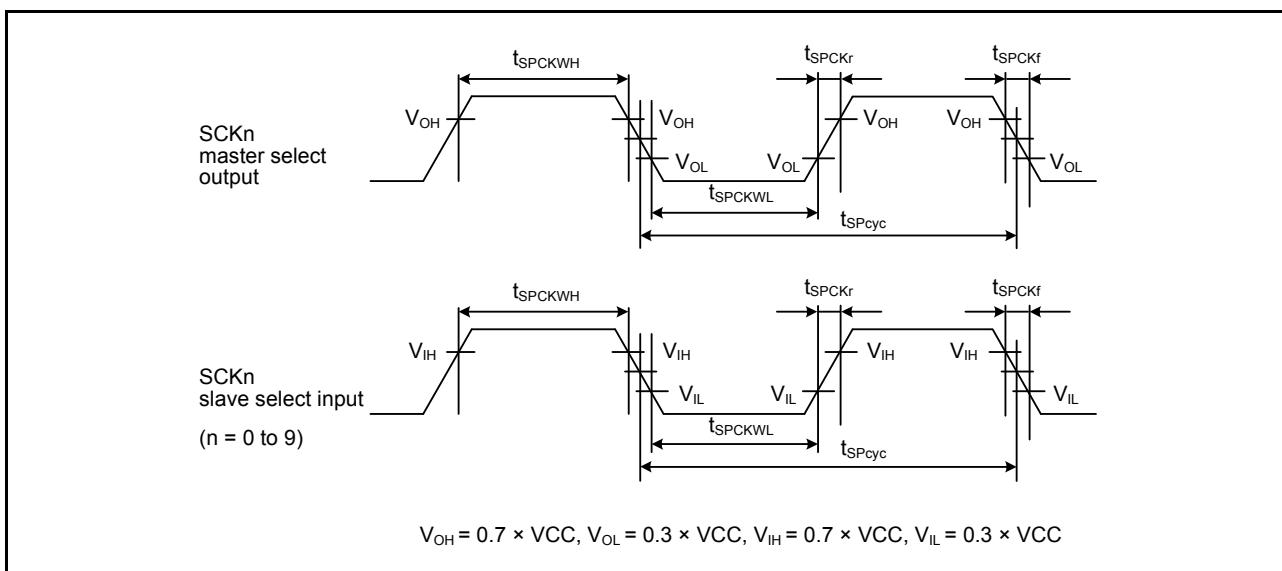


Figure 2.41 SCI simple SPI mode clock timing

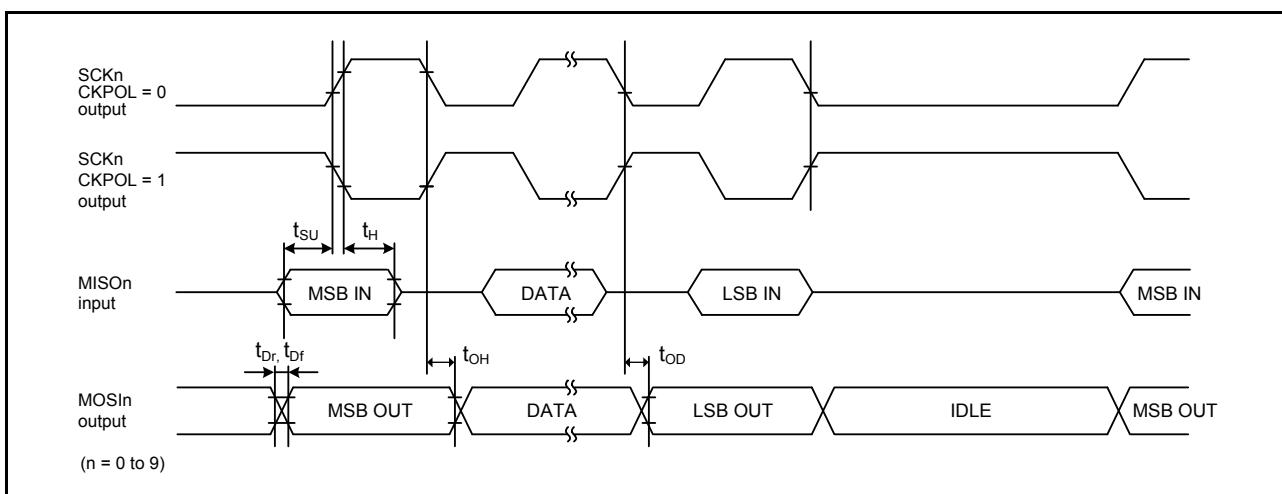


Figure 2.42 SCI simple SPI mode timing for master when CKPH = 1

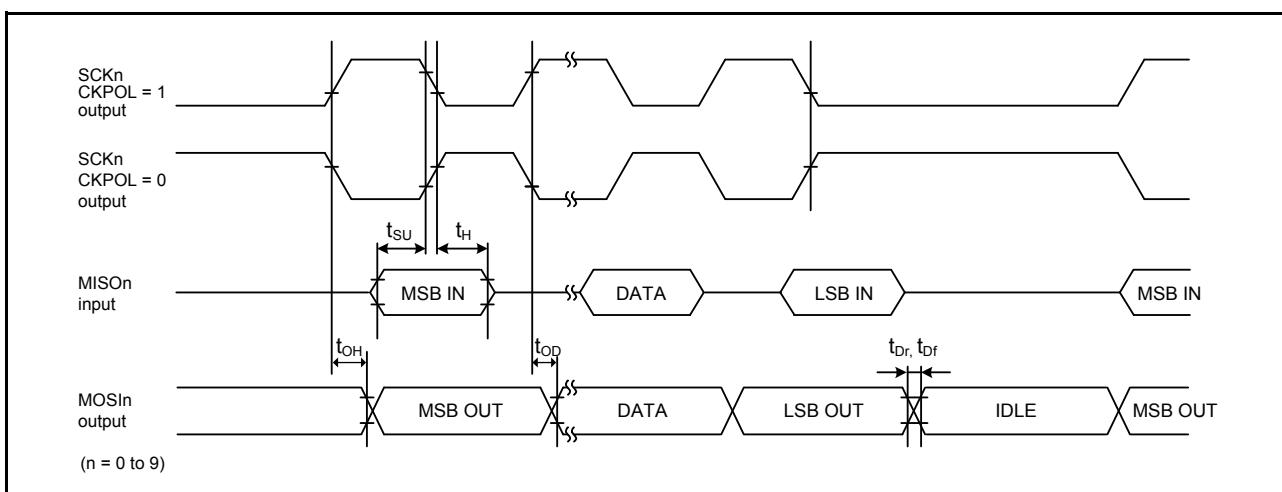


Figure 2.43 SCI simple SPI mode timing for master when CKPH = 0

- Note 2. Must use pins that have a letter ("_A", "_B") to indicate group membership appended to their name as groups. For the SPI interface, the AC portion of the electrical characteristics is measured for each group.
- Note 3. N is set to an integer from 1 to 8 by the SPCKD register.
- Note 4. N is set to an integer from 1 to 8 by the SSLND register.

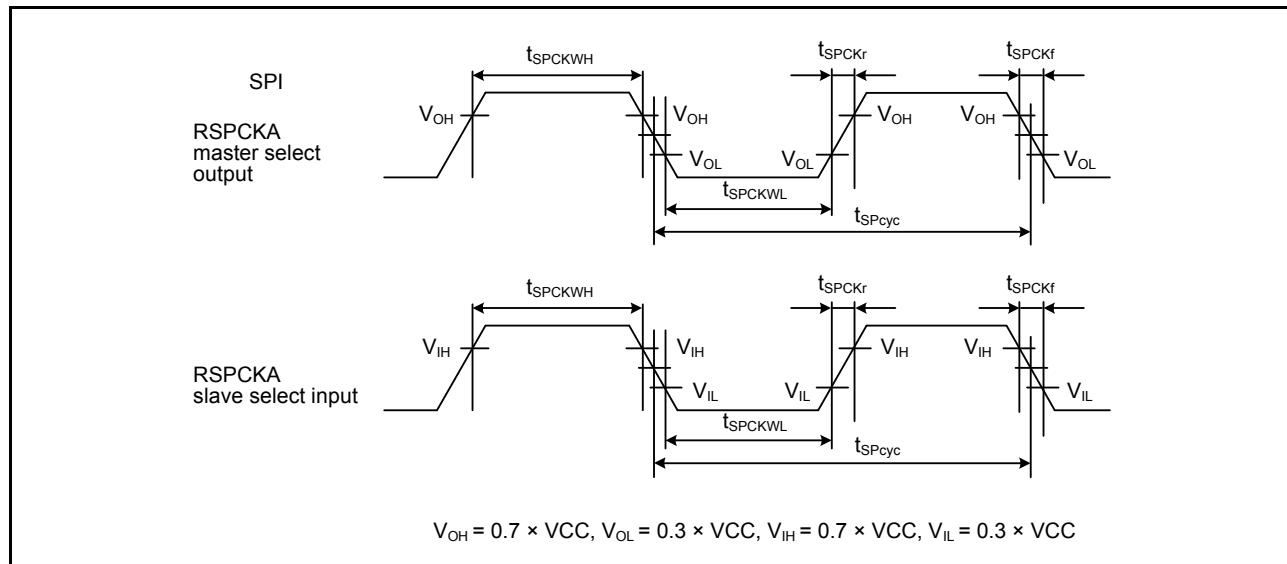


Figure 2.47 SPI clock timing

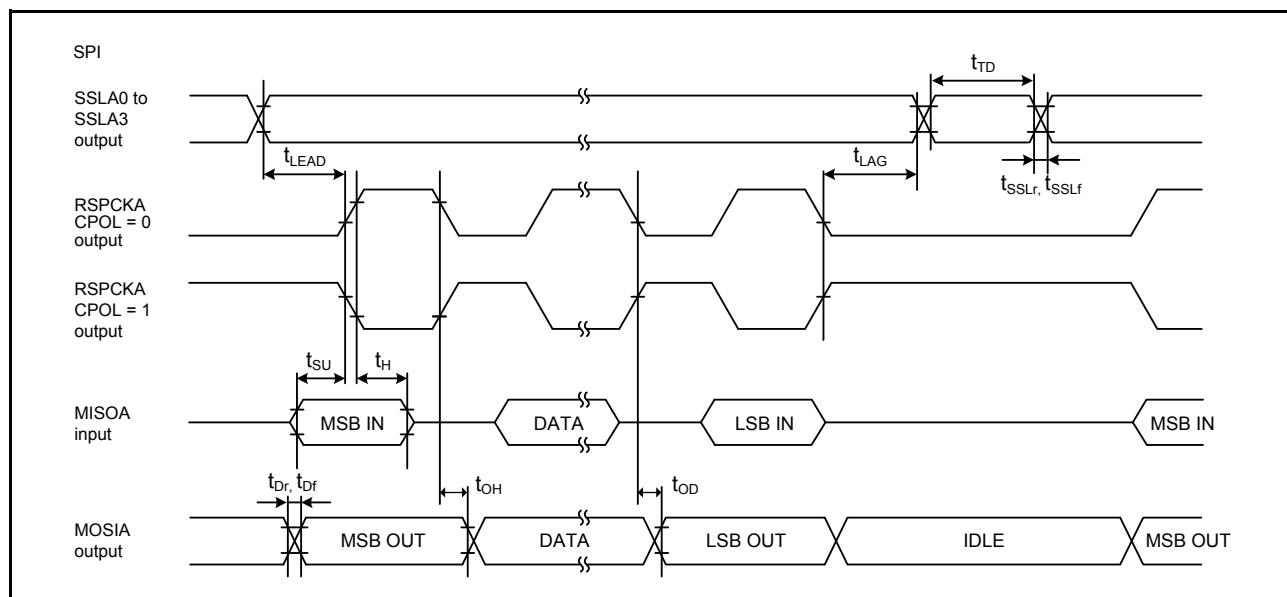


Figure 2.48 SPI timing for master when CPHA = 0

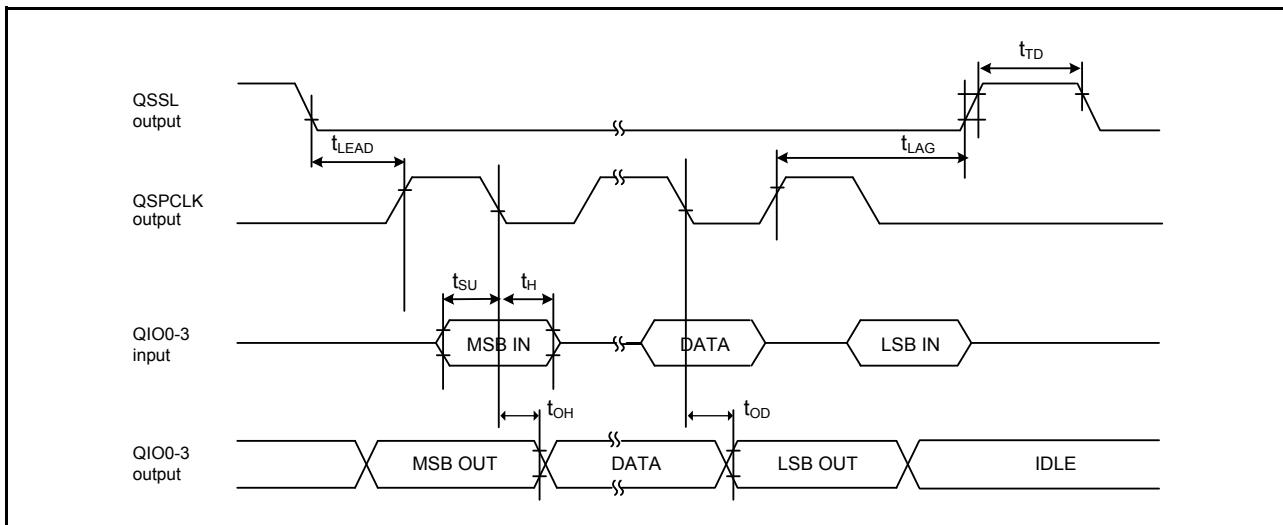


Figure 2.55 Transmit and receive timing

2.3.13 IIC Timing

Table 2.27 IIC timing (1) (1 of 2)

- (1) Conditions: Middle drive output is selected in the port drive capability bit in the PmnPFS register for the following pins: SDA0_B, SCL0_B, SDA1_A, SCL1_A, SDA1_B, SCL1_B.
 (2) The following pins do not require setting: SCL0_A, SDA0_A, SCL2, SDA2.
 (3) Use pins that have a letter appended to their names, for instance “_A” or “_B”, to indicate group membership. For the IIC interface, the AC portion of the electrical characteristics is measured for each group.

Item		Symbol	Min*1	Max	Unit	Test conditions*3
IIC (Standard mode, SMBus) ICFER.FMPE = 0	SCL input cycle time	t_{SCL}	$6(12) \times t_{IICcyc} + 1300$	-	ns	Figure 2.56
	SCL input high pulse width	t_{SCLH}	$3(6) \times t_{IICcyc} + 300$	-	ns	
	SCL input low pulse width	t_{SCLL}	$3(6) \times t_{IICcyc} + 300$	-	ns	
	SCL, SDA input rise time	t_{Sr}	-	1000	ns	
	SCL, SDA input fall time	t_{Sf}	-	300	ns	
	SCL, SDA input spike pulse removal time	t_{SP}	0	$1(4) \times t_{IICcyc}$	ns	
	SDA input bus free time when wakeup function is disabled	t_{BUF}	$3(6) \times t_{IICcyc} + 300$	-	ns	
	SDA input bus free time when wakeup function is enabled	t_{BUF}	$3(6) \times t_{IICcyc} + 4 \times t_{Pcyc} + 300$	-	ns	
	START condition input hold time when wakeup function is disabled	t_{STAH}	$t_{IICcyc} + 300$	-	ns	
	START condition input hold time when wakeup function is enabled	t_{STAH}	$1(5) \times t_{IICcyc} + t_{Pcyc} + 300$	-	ns	
	Repeated START condition input setup time	t_{STAS}	1000	-	ns	
	STOP condition input setup time	t_{STOS}	1000	-	ns	
	Data input setup time	t_{SDAS}	$t_{IICcyc} + 50$	-	ns	
	Data input hold time	t_{SDAH}	0	-	ns	
	SCL, SDA capacitive load	C_b	-	400	pF	

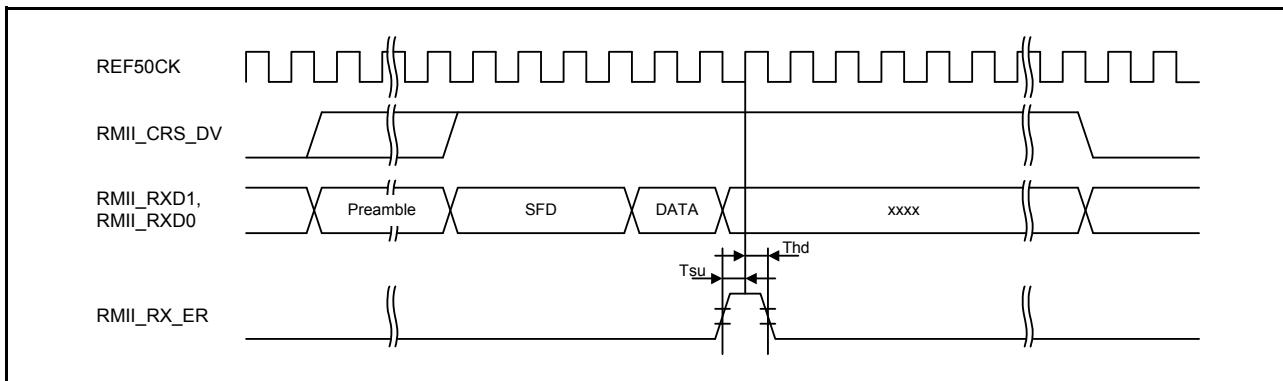


Figure 2.66 RMII reception timing when an error occurs

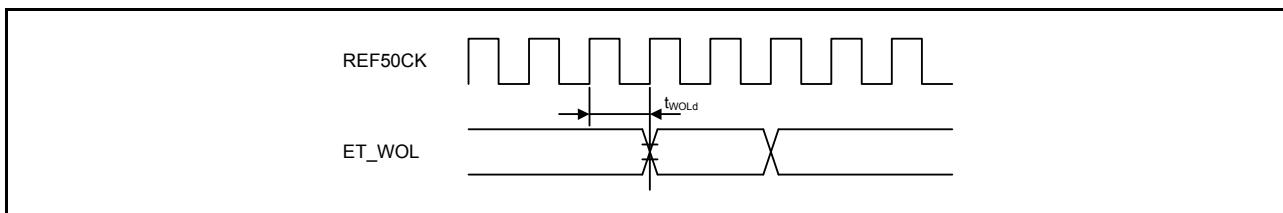


Figure 2.67 WOL output timing for RMII

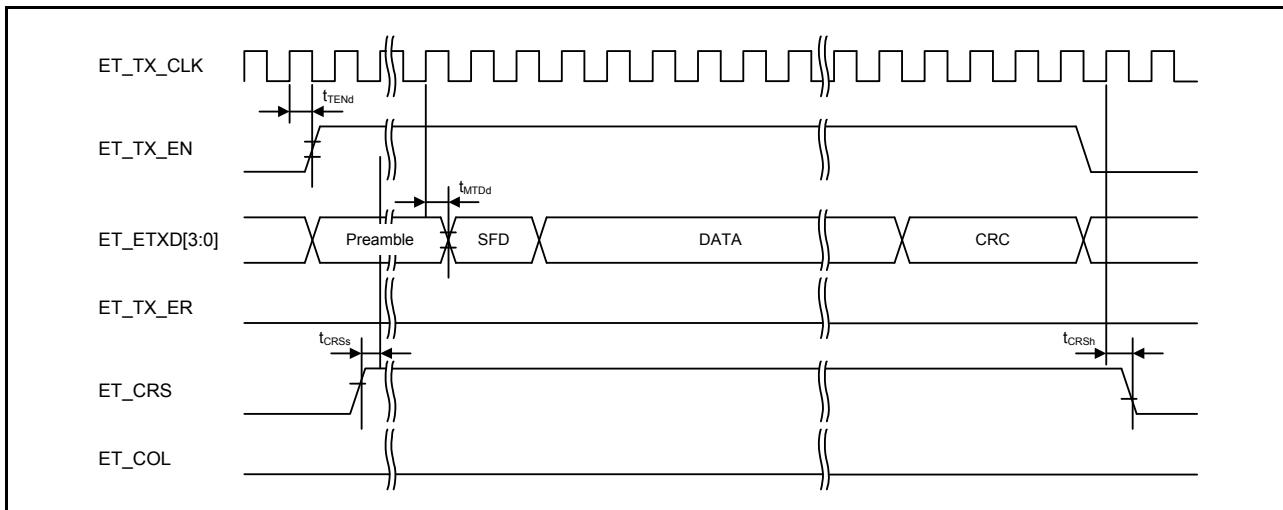


Figure 2.68 MII transmission timing in normal operation

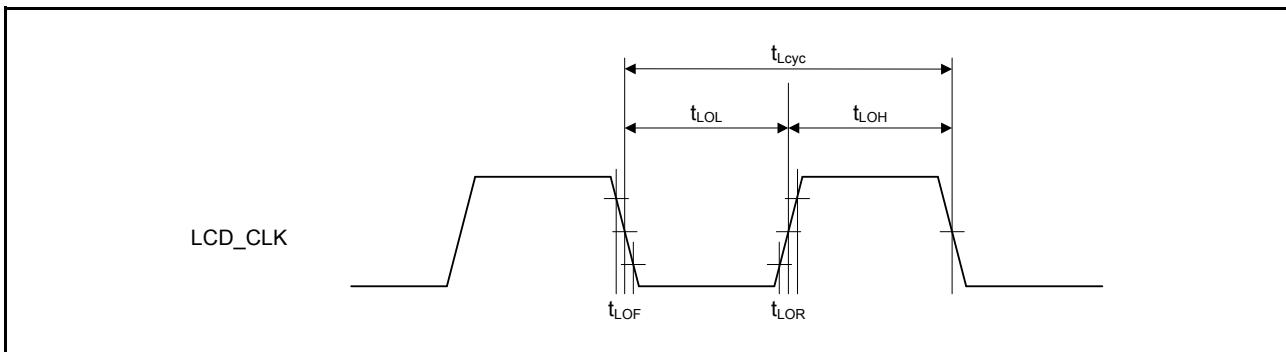


Figure 2.77 LCD_CLK clock output timing

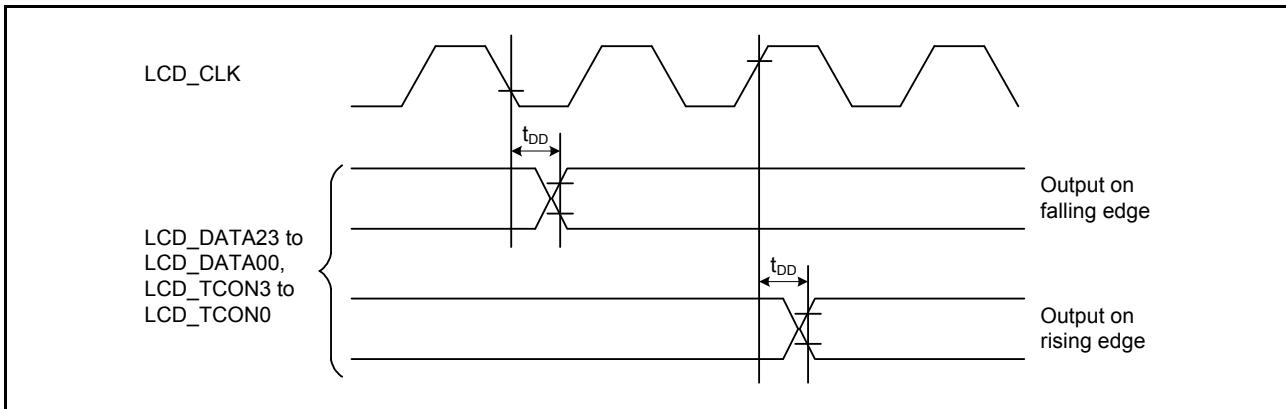


Figure 2.78 Display output timing

2.4 USB Characteristics

2.4.1 USBHS Timing

Table 2.34 USBHS low-speed characteristics for host only (USBHS_DP and USBHS_DM pin characteristics)
Conditions: USBHS_RREF = 2.2 kΩ ± 1%, USBMCLK = 12/20/24 MHz, UCLK = 48 MHz

Item	Symbol	Min	Typ	Max	Unit	Test conditions	
Input characteristics	V _{IH}	2.0	-	-	V	-	-
	V _{IL}	-	-	0.8	V	-	-
	V _{DI}	0.2	-	-	V	USBHS_DP - USBHS_DM	-
	V _{CM}	0.8	-	2.5	V	-	-
Output characteristics	V _{OH}	2.8	-	3.6	V	I _{OH} = -200 μA	-
	V _{OL}	0.0	-	0.3	V	I _{OL} = 2 mA	-
	V _{CRS}	1.3	-	2.0	V	-	Figure 2.79, Figure 2.80
	t _{LR}	75	-	300	ns	-	
	t _{LF}	75	-	300	ns	-	
	t _{LR} / t _{LF}	80	-	125	%	t _{LR} / t _{LF}	-
Pull-up, Pull-down characteristics	R _{pd}	14.25	-	24.80	kΩ	-	-

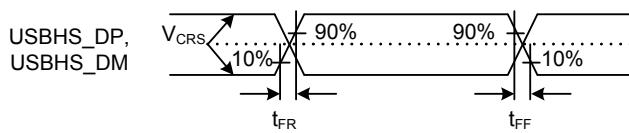


Figure 2.81 USBHS_DP and USBHS_DM output timing in full-speed mode

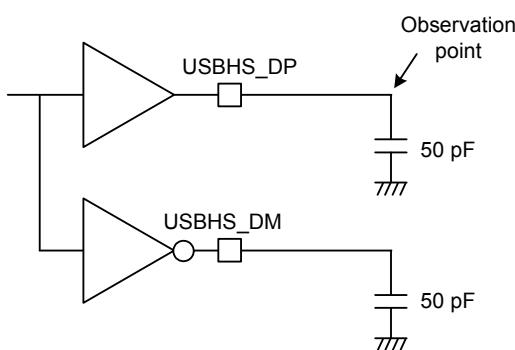


Figure 2.82 Test circuit in full-speed mode

Table 2.36 USBHS high-speed characteristics (USBHS_DP and USBHS_DM pin characteristics)
Conditions: $\text{USBHS_RREF} = 2.2 \text{ k}\Omega \pm 1\%$, $\text{USBMCLK} = 12/20/24 \text{ MHz}$

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Input characteristics	Squelch detect sensitivity	V_{HSSQ}	100	-	150	mV
	Disconnect detect sensitivity	V_{HSDSC}	525	-	625	mV
	Common-mode voltage	V_{HSCM}	-50	-	500	mV
Output characteristics	Idle state	V_{HSOI}	-10.0	-	10	mV
	Output high voltage	V_{HSOH}	360	-	440	mV
	Output low voltage	V_{HSOL}	-10.0	-	10	mV
	Chirp J output voltage (difference)	V_{CHIRPJ}	700	-	1100	mV
	Chirp K output voltage (difference)	V_{CHIRPK}	-900	-	-500	mV
AC characteristics	Rise time	t_{HSR}	500	-	-	ps
	Fall time	t_{HSF}	500	-	-	ps
	Output resistance	Z_{HSDRV}	40.5	-	49.5	Ω

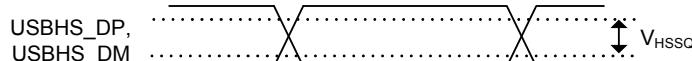


Figure 2.83 USBHS_DP and USBHS_DM squelch detect sensitivity in high-speed mode

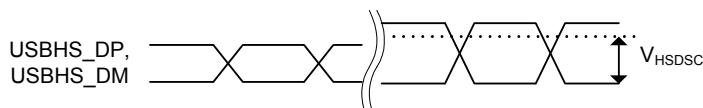
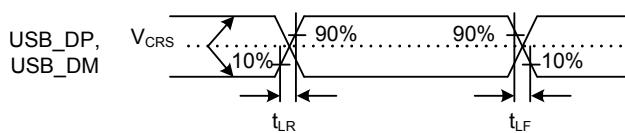
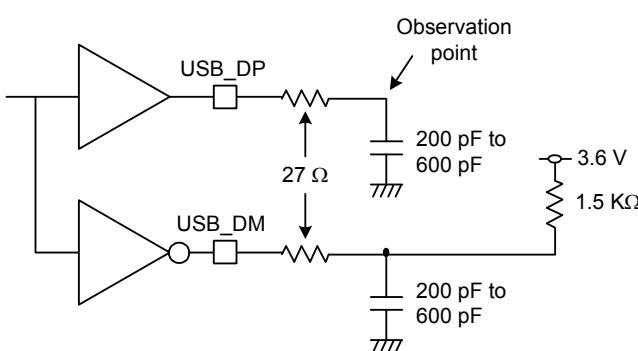


Figure 2.84 USBHS_DP and USBHS_DM disconnect detect sensitivity in high-speed mode

Table 2.38 USBFS low-speed characteristics for host only (USB_DP and USB_DM pin characteristics) (2 of 2)

Conditions: VCC = AVCC0 = VCC_USB = VBATT = 3.0 to 3.6V, $2.7 \leq VREFH0/VREFH \leq AVCC0$, VCC_USBHS = AVCC_USBHS = 3.0 to 3.6 V, UCLK = 48 MHz

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Pull-up and pull-down characteristics	USB_DP and USB_DM pull-down resistance in host controller mode	R _{pd}	14.25	-	24.80	kΩ

**Figure 2.87 USB_DP and USB_DM output timing in low-speed mode****Figure 2.88 Test circuit in low-speed mode****Table 2.39 USBFS full-speed characteristics (USB_DP and USB_DM pin characteristics)**

Conditions: VCC = AVCC0 = VCC_USB = VBATT = 3.0 to 3.6V, $2.7 \leq VREFH0/VREFH \leq AVCC0$, VCC_USBHS = AVCC_USBHS = 3.0 to 3.6 V, UCLK = 48 MHz

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Input characteristics	V _{IH}	2.0	-	-	V	-
	V _{IL}	-	-	0.8	V	-
	V _{DI}	0.2	-	-	V	USB_DP - USB_DM
	V _{CM}	0.8	-	2.5	V	-
Output characteristics	V _{OH}	2.8	-	3.6	V	I _{OH} = -200 μA
	V _{OL}	0.0	-	0.3	V	I _{OL} = 2 mA
	V _{CRS}	1.3	-	2.0	V	Figure 2.89
	t _{LR}	4	-	20	ns	
	t _{LF}	4	-	20	ns	
	t _{LR} / t _{LF}	90	-	111.11	%	t _{FR} / t _{FF}
	Z _{DRV}	28	-	44	Ω	USBFS: Rs = 27 Ω included
Pull-up and pull-down characteristics	R _{pu}	0.900	-	1.575	kΩ	During idle state
		1.425	-	3.090	kΩ	During transmission and reception
	R _{pd}	14.25	-	24.80	kΩ	-

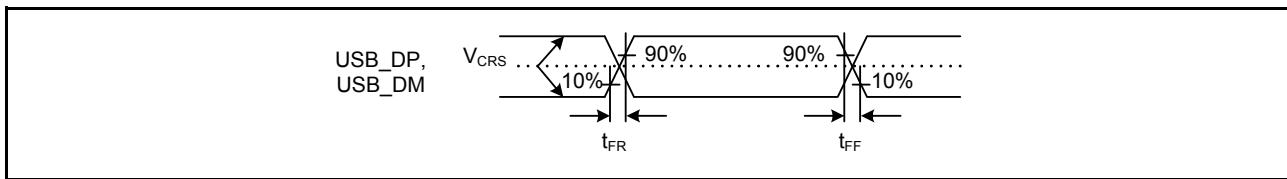


Figure 2.89 USB_DP and USB_DM output timing in full-speed mode

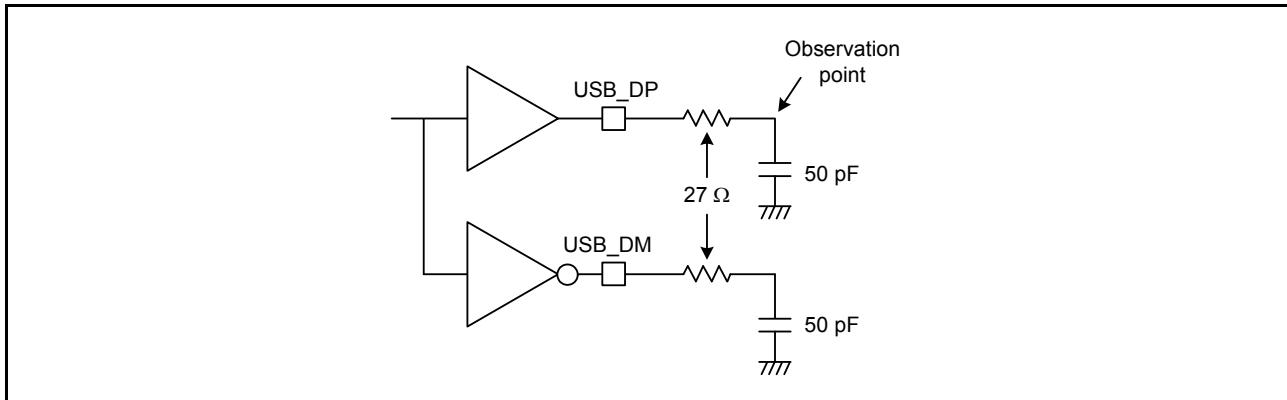


Figure 2.90 Test circuit in full-speed mode

2.5 ADC12 Characteristics

[Normal-precision channel]

Table 2.40 A/D conversion characteristics for unit 0 (1 of 2)

Conditions: PCLKC = 1 to 60 MHz

Item			Min	Typ	Max	Unit	Test conditions
Frequency			1	-	60	MHz	-
Analog input capacitance			-	-	30	pF	-
Quantization error			-	±0.5	-	LSB	-
Resolution			-	-	12	Bits	-
Channel-dedicated sample-and-hold circuits in use (AN000 to AN002)	Conversion time* ¹ (operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	1.06 (0.4 + 0.25)* ²	-	-	μs	<ul style="list-style-type: none"> Sampling of channel-dedicated sample-and-hold circuits in 24 states Sampling in 15 states
	Offset error		-	±1.5	±3.5	LSB	AN000 to AN002 = 0.25 V
	Full-scale error		-	±1.5	±3.5	LSB	AN000 to AN002 = VREFH0 - 0.25 V
	Absolute accuracy		-	±2.5	±5.5	LSB	-
	DNL differential nonlinearity error		-	±1.0	±2.0	LSB	-
	INL integral nonlinearity error		-	±1.5	±3.0	LSB	-
	Holding characteristics of sample-and hold circuits		-	-	20	μs	-
	Dynamic range		0.25	-	VREFH 0 – 0.25	V	-
Channel-dedicated sample-and-hold circuits not in use (AN000 to AN002)	Conversion time* ¹ (operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.48 (0.267)* ²	-	-	μs	Sampling in 16 states
	Offset error		-	±1.0	±2.5	LSB	-
	Full-scale error		-	±1.0	±2.5	LSB	-
	Absolute accuracy		-	±2.0	±4.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±1.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±2.5	LSB	-

Table 2.41 A/D conversion characteristics for unit 1 (2 of 2)

Conditions: PCLKC = 1 to 60 MHz

Item			Min	Typ	Max	Unit	Test conditions
Channel-dedicated sample-and-hold circuits not in use (AN100 to AN102)	Conversion time*1 (Operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.48 (0.267)*2	-	-	μs	Sampling in 16 states
	Offset error		-	±1.0	±2.5	LSB	-
	Full-scale error		-	±1.0	±2.5	LSB	-
	Absolute accuracy		-	±2.0	±4.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±1.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±2.5	LSB	-
High-precision channels (AN103, AN105 to AN107)	Conversion time*1 (Operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.48 (0.267)*2	-	-	μs	Sampling in 16 states
		Max. = 400 Ω	0.40 (0.183)*2	-	-	μs	Sampling in 11 states VCC = AVCC0 = 3.0 to 3.6 V 3.0 V ≤ VREFH ≤ AVCC0
	Offset error		-	±1.0	±2.5	LSB	-
	Full-scale error		-	±1.0	±2.5	LSB	-
	Absolute accuracy		-	±2.0	±4.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±1.5	LSB	-
Normal-precision channels (AN116 to AN119)	Conversion time*1 (Operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.88 (0.667)*2	-	-	μs	Sampling in 40 states
	Offset error		-	±1.0	±5.5	LSB	-
	Full-scale error		-	±1.0	±5.5	LSB	-
	Absolute accuracy		-	±2.0	±7.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±4.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±5.5	LSB	-

Note: These specification values apply when there is no access to the external bus during A/D conversion. If access occurs during A/D conversion, values might not fall within the indicated ranges.

The use of pins AN100 to AN103, AN105 to AN107 as digital outputs is not allowed when the 12-Bit A/D converter is used.

The characteristics apply when AVCC0, AVSS0, VREFH0/VREFH, VREFL0, VREFL, and 12-bit A/D converter input voltage is stable.

Note 1. The conversion time includes the sampling and comparison times. The number of sampling states is indicated for the test conditions.

Note 2. Values in parentheses indicate the sampling time.

Table 2.42 A/D conversion characteristics for simultaneous using of channel-dedicated sample-and-hold circuits in unit0 and unit1

Conditions: PCLKC = 30/60 MHz

Item		Min	Typ	Max	Test conditions
Channel-dedicated sample-and-hold circuits in use with continuous sampling function enabled (AN000 to AN002)	Offset error	-	±1.5	±5.0	• PCLKC = 60 MHz • Sampling in 15 states
	Full-scale error	-	±2.5	±5.0	
	Absolute accuracy	-	±4.0	±8.0	
Channel-dedicated sample-and-hold circuits in use with continuous sampling function enabled (AN100 to AN102)	Offset error	-	±1.5	±5.0	• PCLKC = 30 MHz • Sampling in 7 states
	Full-scale error	-	±2.5	±5.0	
	Absolute accuracy	-	±4.0	±8.0	
Channel-dedicated sample-and-hold circuits in use with continuous sampling function enabled (AN000 to AN002)	Offset error	-	±1.5	±3.5	• PCLKC = 30 MHz • Sampling in 7 states
	Full-scale error	-	±1.5	±3.5	
	Absolute accuracy	-	±3.0	±5.5	
Channel-dedicated sample-and-hold circuits in use with continuous sampling function enabled (AN100 to AN102)	Offset error	-	±1.5	±3.5	
	Full-scale error	-	±1.5	±3.5	
	Absolute accuracy	-	±3.0	±5.5	

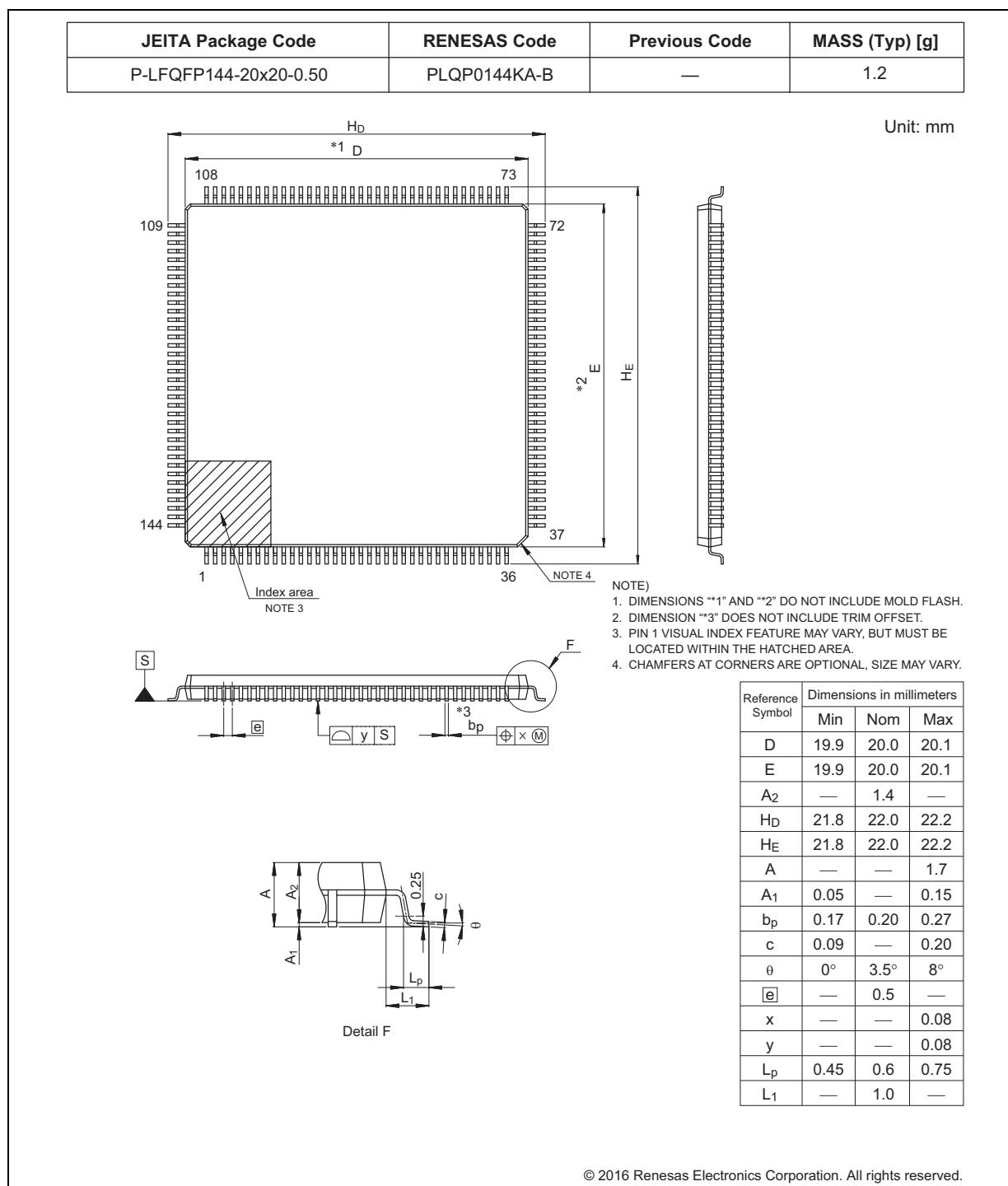


Figure 1.4 144-pin LQFP